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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of **Embedded - Microprocessors**

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

-XF

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	Signal Processing; SPE
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (2)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	-
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8544vtaqg

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



MPC8544E Overview

- Two key (K1, K2, K1) or three key (K1, K2, K3)
- ECB and CBC modes for both DES and 3DES
- AESU—Advanced Encryption Standard unit
 - Implements the Rijndael symmetric key cipher
 - ECB, CBC, CTR, and CCM modes
 - 128-, 192-, and 256-bit key lengths
- AFEU—ARC four execution unit
 - Implements a stream cipher compatible with the RC4 algorithm
 - 40- to 128-bit programmable key
- MDEU—message digest execution unit
 - SHA with 160- or 256-bit message digest
 - MD5 with 128-bit message digest
 - HMAC with either algorithm
- KEU-Kasumi execution unit
 - Implements F8 algorithm for encryption and F9 algorithm for integrity checking
 - Also supports A5/3 and GEA-3 algorithms
- RNG—random number generator
- XOR engine for parity checking in RAID storage applications
- Dual I²C controllers
 - Two-wire interface
 - Multiple master support
 - Master or slave I²C mode support
 - On-chip digital filtering rejects spikes on the bus
- Boot sequencer
 - Optionally loads configuration data from serial ROM at reset via the I²C interface
 - Can be used to initialize configuration registers and/or memory
 - Supports extended I^2C addressing mode
 - Data integrity checked with preamble signature and CRC
- DUART
 - Two 4-wire interfaces (SIN, SOUT, $\overline{\text{RTS}}$, $\overline{\text{CTS}}$)
 - Programming model compatible with the original 16450 UART and the PC16550D
- Local bus controller (LBC)
 - Multiplexed 32-bit address and data bus operating at up to 133 MHz
 - Eight chip selects support eight external slaves
 - Up to eight-beat burst transfers
 - The 32-, 16-, and 8-bit port sizes are controlled by an on-chip memory controller.
 - Two protocol engines available on a per chip select basis:



- Three PCI Express interfaces
 - Two \times 4 link width interfaces and one \times 1 link width interface
 - PCI Express 1.0a compatible
 - Auto-detection of number of connected lanes
 - Selectable operation as root complex or endpoint
 - Both 32- and 64-bit addressing
 - 256-byte maximum payload size
 - Virtual channel 0 only
 - Traffic class 0 only
 - Full 64-bit decode with 32-bit wide windows
- Power management
 - Supports power saving modes: doze, nap, and sleep
 - Employs dynamic power management, which automatically minimizes power consumption of blocks when they are idle
- System performance monitor
 - Supports eight 32-bit counters that count the occurrence of selected events
 - Ability to count up to 512 counter-specific events
 - Supports 64 reference events that can be counted on any of the 8 counters
 - Supports duration and quantity threshold counting
 - Burstiness feature that permits counting of burst events with a programmable time between bursts
 - Triggering and chaining capability
 - Ability to generate an interrupt on overflow
- System access port
 - Uses JTAG interface and a TAP controller to access entire system memory map
 - Supports 32-bit accesses to configuration registers
 - Supports cache-line burst accesses to main memory
 - Supports large block (4-Kbyte) uploads and downloads
 - Supports continuous bit streaming of entire block for fast upload and download
- IEEE Std 1149.1[™]-compliant, JTAG boundary scan
- 783 FC-PBGA package

Power Characteristics



3 Power Characteristics

The estimated typical core power dissipation for the core complex bus (CCB) versus the core frequency for this family of PowerQUICC III devices is shown in Table 4.

Power Mode	Core Frequency (MHz)	Platform Frequency (MHz)	V _{DD} (V)	Junction Temperature (°C)	Power (W)	Notes
Typical	667	333	1.0	65	2.6	1, 2
Thermal				105	4.5	1, 3
Maximum					7.15	1, 4
Typical	800	400	1.0	65	2.9	1, 2
Thermal				105	4.8	1, 3
Maximum					7.35	1, 4
Typical	1000	400	1.0	65	3.6	1, 2
Thermal				105	5.3	1, 3
Maximum					7.5	1, 4
Typical	1067	533	1.0	65	3.9	1, 2
Thermal				105	6.0	1, 3
Maximum				105	7.7	1, 4

Table 4. MPC8544ECore Power Dissipation

Notes:

1. These values specify the power consumption at nominal voltage and apply to all valid processor bus frequencies and configurations. The values do not include power dissipation for I/O supplies.

- Typical power is an average value measured at the nominal recommended core voltage (V_{DD}) and 65°C junction temperature (see Table 2) while running the Dhrystone 2.1 benchmark.
- Thermal power is the average power measured at nominal core voltage (V_{DD}) and maximum operating junction temperature (see Table 2) while running the Dhrystone 2.1 benchmark.
- 4. Maximum power is the maximum power measured at nominal core voltage (V_{DD}) and maximum operating junction temperature (see Table 2) while running a smoke test which includes an entirely L1-cache-resident, contrived sequence of instructions which keep the execution unit maximally busy.

4 Input Clocks

This section contains the following subsections:

- Section 4.1, "System Clock Timing"
- Section 4.2, "Real-Time Clock Timing"
- Section 4.3, "eTSEC Gigabit Reference Clock Timing"
- Section 4.4, "Platform to FIFO Restrictions"
- Section 4.5, "Other Input Clocks"



Input Clocks

4.1 System Clock Timing

Table 5 provides the system clock (SYSCLK) AC timing specifications for the MPC8544E.

Table 5. SYSCLK AC Timing Specifications

At recommended operating conditions (see Table 2) with $OV_{DD} = 3.3 V \pm 165 mV$.

Parameter/Condition	Symbol	Min	Typical	Мах	Unit	Notes
SYSCLK frequency	f _{SYSCLK}	33	—	133	MHz	1
SYSCLK cycle time	t _{SYSCLK}	7.5	—	30.3	ns	_
SYSCLK rise and fall time	t _{KH} , t _{KL}	0.6	1.0	2.1	ns	2
SYSCLK duty cycle	t _{KHK} ∕t _{SYSCLK}	40	—	60	%	_
SYSCLK jitter	_	—	—	±150	ps	3, 4

Notes:

1. **Caution:** The CCB clock to SYSCLK ratio and e500 core to CCB clock ratio settings must be chosen such that the resulting SYSCLK frequency, e500 (core) frequency, and CCB clock frequency do not exceed their respective maximum or minimum operating frequencies. Refer to Section 19.2, "CCB/SYSCLK PLL Ratio," and Section 19.3, "e500 Core PLL Ratio," for ratio settings.

2. Rise and fall times for SYSCLK are measured at 0.6 and 2.7 V.

3. This represents the total input jitter-short- and long-term.

4. The SYSCLK driver's closed loop jitter bandwidth should be <500 kHz at -20 dB. The bandwidth must be set low to allow cascade-connected PLL-based devices to track SYSCLK drivers with the specified jitter.

4.1.1 SYSCLK and Spread Spectrum Sources

Spread spectrum clock sources are an increasingly popular way to control electromagnetic interference emissions (EMI) by spreading the emitted noise to a wider spectrum and reducing the peak noise magnitude in order to meet industry and government requirements. These clock sources intentionally add long-term jitter in order to diffuse the EMI spectral content. The jitter specification given in Table 5 considers short-term (cycle-to-cycle) jitter only and the clock generator's cycle-to-cycle output jitter should meet the MPC8544E input cycle-to-cycle jitter requirement. Frequency modulation and spread are separate concerns, and the MPC8544E is compatible with spread spectrum sources if the recommendations listed in Table 6 are observed.

Table 6. Spread Spectrum Clock Source Recommendations

At recommended operating conditions. See Table 2.

Parameter	Min	Мах	Unit	Notes
Frequency modulation	20	60	kHz	—
Frequency spread	0	1.0	%	1

Note:

1. SYSCLK frequencies resulting from frequency spreading, and the resulting core and VCO frequencies, must meet the minimum and maximum specifications given in Table 5.

It is imperative to note that the processor's minimum and maximum SYSCLK, core, and VCO frequencies must not be exceeded regardless of the type of clock source. Therefore, systems in which the processor is operated at its maximum rated e500 core frequency should avoid violating the stated limits by using down-spreading only.



DDR and DDR2 SDRAM

6.2.2 DDR SDRAM Output AC Timing Specifications

Table 18 provides the output AC timing specifications for the DDR SDRAM interface.

Table 18. DDR SDRAM Output AC Timing Specifications

At recommended operating conditions.

Parameter	Symbol ¹	Min	Мах	Unit	Notes
MCK[n] cycle time, MCK[n]/MCK[n] crossing	t _{MCK}	3.75	6	ns	2
ADDR/CMD output setup with respect to MCK	t _{DDKHAS}			ns	3
533 MHz 400 MHz 333 MHz		1.48 1.95 2.40			7
ADDR/CMD output hold with respect to MCK	t _{DDKHAX}			ns	3
533 MHz 400 MHz 333 MHz		1.48 1.95 2.40			7
MCS[n] output setup with respect to MCK	t _{DDKHCS}			ns	3
533 MHz 400 MHz 333 MHz		1.48 1.95 2.40			7
MCS[n] output hold with respect to MCK	t _{DDKHCX}			ns	3
533 MHz 400 MHz 333 MHz		1.48 1.95 2.40			7
MCK to MDQS Skew	t _{DDKHMH}	-0.6	0.6	ns	4
MDQ/MECC/MDM output setup with respect to MDQS	^t DDKHDS, t _{DDKLDS}			ps	5
533 MHz 400 MHz 333 MHz		538 700 900			7
MDQ/MECC/MDM output hold with respect to MDQS	t _{DDKHDX,} t _{DDKLDX}			ps	5
533 MHz 400 MHz 333 MHz		538 700 900			7 — —
MDQS preamble	t _{DDKHMP}	0.75 x tMCK	—	ns	6



Enhanced Three-Speed Ethernet (eTSEC), MII Management

Table 19. DUART DC Electrical Characteristics (continued)

Parameter	Symbol	Min	Мах	Unit	Notes
Low-level output voltage ($OV_{DD} = min, I_{OL} = 2 mA$)	V _{OL}		0.4	V	

Note:

1. Note that the symbol V_{IN} , in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.2 DUART AC Electrical Specifications

Table 20 provides the AC timing parameters for the DUART interface.

Table 20. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	CCB clock/1,048,576	baud	1
Maximum baud rate	CCB clock/16	baud	2
Oversample rate	16	—	3

Notes:

1. CCB clock refers to the platform clock.

2. Actual attainable baud rate will be limited by the latency of interrupt processing.

3. The middle of a start bit is detected as the eighth sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each sixteenth sample.

8 Enhanced Three-Speed Ethernet (eTSEC), MII Management

This section provides the AC and DC electrical characteristics for enhanced three-speed and MII management.

8.1 Enhanced Three-Speed Ethernet Controller (eTSEC) (10/100/1000 Mbps)—SGMII/GMII/MII/TBI/RGMII/RTBI/RMII/FIFO Electrical Characteristics

The electrical characteristics specified here apply to all gigabit media independent interface (GMII), 8-bit FIFO interface (FIFO), serial gigabit media independent interface (SGMII), media independent interface (MII), ten-bit interface (TBI), reduced gigabit media independent interface (RGMII), reduced ten-bit interface (RTBI), and reduced media independent interface (RMII) signals except management data input/output (MDIO) and management data clock (MDC). The 8-bit FIFO interface can operate at 3.3 or 2.5 V. The RGMII and RTBI interfaces are defined for 2.5 V, while the MII, GMII, TBI, and RMII interfaces can be operated at 3.3 or 2.5 V. Whether the GMII, MII, or TBI interface is operated at 3.3 or 2.5 V, the timing is compliant with IEEE 802.3. The RGMII and RTBI interfaces follow the *Reduced Gigabit Media-Independent Interface (RGMII) Specification Version 1.3* (12/10/2000). The RMII interfaces follows the *RMII Consortium RMII Specification Version 1.2* (3/20/1998). The SGMII interfaces follow the *Serial Gigabit Media-Independent Interface (SGMII) Specification Version 1.8*. The electrical characteristics for MDIO and MDC are specified in Section 9, "Ethernet Management Interface Electrical



8.3 SGMII Interface Electrical Characteristics

Each SGMII port features a 4-wire AC-coupled serial link from the dedicated SerDes 2 interface of MPC8544E as shown in Figure 7, where C_{TX} is the external (on board) AC-coupled capacitor. Each output pin of the SerDes transmitter differential pair features 50- Ω output impedance. Each input of the SerDes receiver differential pair features 50- Ω on-die termination to SGND_SRDS2 (xcorevss). The reference circuit of the SerDes transmitter and receiver is shown in Figure 7.

When an eTSEC port is configured to operate in SGMII mode, the parallel interface's output signals of this eTSEC port can be left floating. The input signals should be terminated based on the guidelines described in Section 21.5, "Connection Recommendations," as long as such termination does not violate the desired POR configuration requirement on these pins, if applicable.

When operating in SGMII mode, the eTSEC EC_GTX_CLK125 clock is not required for this port. Instead, SerDes reference clock is required on SD2_REF_CLK and SD2_REF_CLK pins.

8.3.1 AC Requirements for SGMII SD2_REF_CLK and SD2_REF_CLK

Table 23 lists the SGMII SerDes reference clock AC requirements. Please note that SD2_REF_CLK and SD2_REF_CLK are not intended to be used with, and should not be clocked by, a spread spectrum clock source.

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
t _{REF}	REFCLK cycle time	—	10 (8)	_	ns	1
t _{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	100	ps	—
t _{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	-50	—	50	ps	—

Table 23. SD2_REF_CLK and SD2_REF_CLK AC Requirements

Note:

1. 8 ns applies only when 125 MHz SerDes2 reference clock frequency is selected via cfg_srds_sgmii_refclk during POR.

8.3.2 SGMII Transmitter and Receiver DC Electrical Characteristics

Table 24 and Table 25 describe the SGMII SerDes transmitter and receiver AC-coupled DC electrical characteristics. Transmitter DC characteristics are measured at the transmitter outputs (SD2_TX[n] and SD2_TX[n]) as depicted in Figure 8.

Parameter	Symbol	Min	Тур	Мах	Unit	Notes
Supply Voltage	V_{DD_SRDS2}	0.95	1.0	1.05	V	
Output high voltage	V _{OH}	_		V_{OS} -max + $ V_{OD} _{-max}/2$	mV	1
Output low voltage	V _{OL}	V_{OS} -min $- V_{OD} _{-max}/2$		_	mV	I
Output ringing	V _{RING}	—		10	%	_

Table 24. DC Transmitter Electrical Characteristics



Enhanced Three-Speed Ethernet (eTSEC), MII Management

Parameter		Symbol	Min	Тур	Max	Unit	Notes
Input differential voltage	LSTS = 0	V _{rx_diffpp}	100	—	1200	mV	2, 4
	LSTS = 1	1	175	—			
Loss of signal threshold	LSTS = 0	VI _{os}	30	—	100	mV	3, 4
	LSTS = 1	1	65	—	175		
Input AC common mode voltage		V _{cm_acpp}	—	—	100	mV	5.
Receiver differential input impedar	ice	Zrx_diff	80	—	120	Ω	—
Receiver common mode input imp	edance	Zrx_cm	20	—	35	Ω	—
Common mode input voltage		Vcm	xcorevss	—	xcorevss	V	6

Table 25. DC Receiver Electrical Characteristics (continued)

Notes:

1. Input must be externally AC-coupled.

- 2. $V_{RX_DIFFp-p}$ is also referred to as peak-to-peak input differential voltage
- 3. The concept of this parameter is equivalent to the electrical idle detect threshold parameter in PCI Express. Refer to Section 17.4.3, "Differential Receiver (RX) Input Specifications," for further explanation.
- 4. The LSTS shown in this table refers to the LSTSCD bit field of MPC8544E SerDes 2 control register 1.
- 5. V_{CM ACp-p} is also referred to as peak-to-peak AC common mode voltage.
- 6. On-chip termination to SGND_SRDS2 (xcorevss).

8.4 SGMII AC Timing Specifications

This section describes the SGMII transmit and receive AC timing specifications. Transmitter and receiver characteristics are measured at the transmitter outputs ($SD2_TX[n]$ and $\overline{SD2_TX[n]}$) or at the receiver inputs ($SD2_RX[n]$ and $\overline{SD2_RX[n]}$) as depicted in Figure 10, respectively.

8.4.1 SGMII Transmit AC Timing Specifications

Table 26 provides the SGMII transmit AC timing targets. A source synchronous clock is not provided.

Table 26. SGMII Transmit AC Timing Specifications

At recommended operating conditions with XVDD_SRDS2 = $1.0 V \pm 5\%$.

Parameter	Symbol	Min	Тур	Мах	Unit	Notes
Deterministic jitter	J _D	—	—	0.17	UI p-p	—
Total jitter	J _T	—	—	0.35	UI p-p	—
Unit interval	UI	799.92	800	800.08	ps	2
V _{OD} fall time (80%–20%)	t _{fall}	50	—	120	ps	—
V _{OD} rise time (20%–80%)	t _{rise}	50	—	120	ps	—

Notes;

1. Source synchronous clock is not supported.

2. Each UI value is 800 ps \pm 100 ppm.



Table 45. Local Bus General Timing Parameters (BV_{DD} = 3.3 V)—PLL Enabled (continued)

Parameter	Symbol ¹	Min	Мах	Unit	Notes
Local bus clock to output high impedance for LAD/LDP	t _{LBKHOZ2}	_	2.5	ns	5

Notes:

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
</sub>

2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.

3. All signals are measured from $BV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times BV_{DD}$ of the signal in question for 3.3-V signaling levels.

4. Input timings are measured at the pin.

5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.

- 6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
- 7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at BV_{DD}/2.

Table 46 describes the general timing parameters of the local bus interface at $BV_{DD} = 2.5$ V.

Table 46. Local Bus General Timing Parameters (BV_{DD} = 2.5 V)—PLL Enabled

Parameter	Symbol ¹	Min	Мах	Unit	Notes
Local bus cycle time	t _{LBK}	7.5	12	ns	2
Local bus duty cycle	t _{LBKH/} t _{LBK}	43	57	%	—
LCLK[n] skew to LCLK[m] or LSYNC_OUT	t _{lbkskew}	—	150	ps	7
Input setup to local bus clock (except LUPWAIT)	t _{LBIVKH1}	2.4	—	ns	3, 4
LUPWAIT input setup to local bus clock	t _{LBIVKH2}	1.8	—	ns	3, 4
Input hold from local bus clock (except LUPWAIT)	t _{LBIXKH1}	1.1	—	ns	3, 4
LUPWAIT input hold from local bus clock	t _{LBIXKH2}	1.1	—	ns	3, 4
LALE output transition to LAD/LDP output transition (LATCH setup and hold time)	t _{lbotot}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	t _{LBKHOV1}	_	2.8	ns	_
Local bus clock to data valid for LAD/LDP	t _{LBKHOV2}	—	2.8	ns	3
Local bus clock to address valid for LAD	t _{LBKHOV3}	—	2.8	ns	3
Local bus clock to LALE assertion	t _{LBKHOV4}	—	2.8	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	t _{LBKHOX1}	0.8	—	ns	3
Output hold from local bus clock for LAD/LDP	t _{LBKHOX2}	0.8	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	t _{LBKHOZ1}	—	2.6	ns	5



Figure 37 provides the boundary-scan timing diagram.



Figure 37. Boundary-Scan Timing Diagram

13 I²C

This section describes the DC and AC electrical characteristics for the I²C interfaces of the MPC8544E.

13.1 I²C DC Electrical Characteristics

Table 51 provides the DC electrical characteristics for the I²C interfaces.

Table 51. I²C DC Electrical Characteristics

At recommended operating conditions with OV_{DD} of 3.3 V ± 5%.

Parameter	Symbol	Min	Мах	Unit	Notes
Input high voltage level	V _{IH}	$0.7\times \text{OV}_{\text{DD}}$	OV _{DD} + 0.3	V	_
Input low voltage level	V _{IL}	-0.3	$0.3\times\text{OV}_{\text{DD}}$	V	_
Low level output voltage	V _{OL}	0	$0.2\times\text{OV}_{\text{DD}}$	V	1
Pulse width of spikes which must be suppressed by the input filter	t _{I2KHKL}	0	50	ns	2
Input current each I/O pin (input voltage is between $0.1 \times OV_{DD}$ and $0.9 \times OV_{DD}$ (max)	I	-10	10	μA	3
Capacitance for each I/O pin	CI	_	10	pF	_

Notes:

1. Output voltage (open drain or open collector) condition = 3 mA sink current.

2. Refer to the MPC8544EPowerQUICC III Integrated Communications Host Processor Reference Manual for information on the digital filter used.

3. I/O pins will obstruct the SDA and SCL lines if $\ensuremath{\mathsf{OV}_{\text{DD}}}$ is switched off.



PCI

15.2 PCI AC Electrical Specifications

This section describes the general AC timing parameters of the PCI bus. Note that the SYSCLK signal is used as the PCI input clock. Table 56 provides the PCI AC timing specifications at 66 MHz.

Parameter	Symbol ¹	Min	Max	Unit	Notes
SYSCLK to output valid	t _{PCKHOV}	_	7.4	ns	2, 3
Output hold from SYSCLK	t _{PCKHOX}	2.0	_	ns	2
SYSCLK to output high impedance	t _{PCKHOZ}	_	14	ns	2, 4
Input setup to SYSCLK	t _{PCIVKH}	3.7	_	ns	2, 5
Input hold from SYSCLK	t _{PCIXKH}	0.5	_	ns	2, 5
REQ64 to HRESET ⁹ setup time	t _{PCRVRH}	$10 \times t_{SYS}$	_	clocks	6, 7
HRESET to REQ64 hold time	t _{PCRHRX}	0	50	ns	7
HRESET high to first FRAME assertion	t _{PCRHFV}	10	_	clocks	8
Rise time (20%–80%)	t _{PCICLK}	0.6	2.1	ns	
Fall time (20%–80%)	t _{PCICLK}	0.6	2.1	ns	

Table 56. PCI AC Timin	g Specifications at 66 MHz
------------------------	----------------------------

Notes:

The symbols used for timing specifications follow the pattern of t<sub>(first two letters of functional block)(signal)(state)(reference)(state) for inputs and t<sub>(first two letters of functional block)(reference)(state)(signal)(state) for outputs. For example, t_{PCIVKH} symbolizes PCI timing (PC) with respect to the time the input signals (I) reach the valid state (V) relative to the SYSCLK clock, t_{SYS}, reference (K) going to the high (H) state or setup time. Also, t_{PCRHFV} symbolizes PCI timing (PC) with respect to the time hard reset (R) went high (H) relative to the frame signal (F) going to the valid (V) state.
</sub></sub>

- 2. See the timing measurement conditions in the PCI 2.2 Local Bus Specifications.
- 3. All PCI signals are measured from $OV_{DD}/2$ of the rising edge of PCI_SYNC_IN to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V PCI signaling levels.
- 4. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
- 5. Input timings are measured at the pin.
- The timing parameter t_{SYS} indicates the minimum and maximum CLK cycle times for the various specified frequencies. The system clock period must be kept within the minimum and maximum defined ranges. For values see Section 19, "Clocking."
- 7. The setup and hold time is with respect to the rising edge of HRESET.
- 8. The timing parameter t_{PCRHFV} is a minimum of 10 clocks rather than the minimum of 5 clocks in the PCI 2.2 Local Bus Specifications.
- 9. The reset assertion timing requirement for $\overline{\text{HRESET}}$ is 100 $\mu\text{s}.$

Figure 41 provides the AC test load for PCI.



Figure 41. PCI AC Test Load



High-Speed Serial Interfaces (HSSI)

Using this waveform, the definitions are as follows. To simplify illustration, the following definitions assume that the SerDes transmitter and receiver operate in a fully symmetrical differential signaling environment.

1. Single-Ended Swing

The transmitter output signals and the receiver input signals SDn_TX , $\overline{SDn_TX}$, SDn_RX and $\overline{SDn_RX}$ each have a peak-to-peak swing of A - B Volts. This is also referred as each signal wire's Single-Ended Swing.

2. Differential Output Voltage, VOD (or Differential Output Swing):

The Differential Output Voltage (or Swing) of the transmitter, V_{OD} , is defined as the difference of the two complimentary output voltages: $V_{SDn_TX} - V_{\overline{SDn_TX}}$. The V_{OD} value can be either positive or negative.

3. Differential Input Voltage, V_{ID} (or Differential Input Swing):

The Differential Input Voltage (or Swing) of the receiver, V_{ID} , is defined as the difference of the two complimentary input voltages: $V_{SDn_RX} - V_{\overline{SDn_RX}}$. The V_{ID} value can be either positive or negative.

4. Differential Peak Voltage, VDIFFp

The peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak Voltage, $V_{DIFFp} = |A - B|$ Volts.

5. Differential Peak-to-Peak, V_{DIFFp-p}

Since the differential output signal of the transmitter and the differential input signal of the receiver each range from A – B to –(A – B) Volts, the peak-to-peak value of the differential transmitter output signal or the differential receiver input signal is defined as Differential Peak-to-Peak Voltage, $V_{DIFFp-p} = 2*V_{DIFFp} = 2*|(A – B)|$ Volts, which is twice of differential swing in amplitude, or twice of the differential peak. For example, the output differential peak-peak voltage can also be calculated as $V_{TX-DIFFp-p} = 2*|V_{OD}|$.

6. Differential Waveform

The differential waveform is constructed by subtracting the inverting signal ($\overline{\text{SD}n_TX}$, for example) from the non-inverting signal ($\overline{\text{SD}n_TX}$, for example) within a differential pair. There is only one signal trace curve in a differential waveform. The voltage represented in the differential waveform is not referenced to ground. Refer to Figure 44 as an example for differential waveform.

7. Common Mode Voltage, V_{cm}

The Common Mode Voltage is equal to one half of the sum of the voltages between each conductor of a balanced interchange circuit and ground. In this example, for SerDes output, $V_{cm_out} = V_{SDn_TX} + V_{\overline{SDn_TX}} = (A + B)/2$, which is the arithmetic mean of the two complimentary output voltages within a differential pair. In a system, the common mode voltage may often differ from one component's output to the other's input. Sometimes, it may be even different between the receiver input and driver output circuits within the same component. It is also referred as the DC offset in some occasions.



Figure 49 shows the SerDes reference clock connection reference circuits for HCSL type clock driver. It assumes that the DC levels of the clock driver chip is compatible with MPC8544E SerDes reference clock input's DC requirement.



Figure 49. DC-Coupled Differential Connection with HCSL Clock Driver (Reference Only)

Figure 50 shows the SerDes reference clock connection reference circuits for LVDS type clock driver. Since LVDS clock driver's common mode voltage is higher than the MPC8544E SerDes reference clock input's allowed range (100 to 400mV), AC-coupled connection scheme must be used. It assumes the LVDS output driver features $50-\Omega$ termination resistor. It also assumes that the LVDS transmitter establishes its own common mode level without relying on the receiver or other external component.



Figure 50. AC-Coupled Differential Connection with LVDS Clock Driver (Reference Only)

Figure 51 shows the SerDes reference clock connection reference circuits for LVPECL type clock driver. Since LVPECL driver's DC levels (both common mode voltages and output swing) are incompatible with MPC8544E SerDes reference clock input's DC requirement, AC-coupling has to be used. Figure 51



Symbol	Parameter	Min	Nom	Мах	Unit	Comments
V _{TX-RCV-DETECT}	Amount of voltage change allowed during receiver detection	_	_	600	mV	The total amount of voltage change that a transmitter can apply to sense whether a low impedance receiver is present. See Note 6.
V _{TX-DC-CM}	TX DC common mode voltage	0	—	3.6	V	The allowed DC common mode voltage under any conditions. See Note 6.
I _{TX-SHORT}	TX short circuit current limit	—	—	90	mA	The total current the transmitter can provide when shorted to its ground.
T _{TX-IDLE-MIN}	Minimum time spent in electrical idle	50	_	_	UI	Minimum time a transmitter must be in electrical idle utilized by the receiver to start looking for an electrical idle exit after successfully receiving an electrical idle ordered set.
T _{TX-IDLE-SET-TO-IDLE}	Maximum time to transition to a valid electrical idle after sending an electrical Idle ordered set	_	_	20	UI	After sending an electrical idle ordered set, the transmitter must meet all electrical idle specifications within this time. This is considered a debounce time for the transmitter to meet electrical idle after transitioning from LO.
T _{TX} -IDLE-TO-DIFF-DATA	Maximum time to transition to valid TX specifications after leaving an electrical idle condition	_	_	20	UI	Maximum time to meet all TX specifications when transitioning from electrical idle to sending differential data. This is considered a debounce time for the TX to meet all TX specifications after leaving electrical idle.
RL _{TX-DIFF}	Differential return loss	12	—	—	dB	Measured over 50 MHz to 1.25 GHz. See Note 4.
RL _{TX-CM}	Common mode return loss	6	_	_	dB	Measured over 50 MHz to 1.25 GHz. See Note 4.
Z _{TX-DIFF-DC}	DC differential TX impedance	80	100	120	Ω	TX DC differential mode low impedance.
Z _{TX-DC}	Transmitter DC impedance	40	—	—	Ω	Required TX D+ as well as D– DC Impedance during all states.
L _{TX-SKEW}	Lane-to-lane output skew	_	—	500 + 2 UI	ps	Static skew between any two transmitter lanes within a single link.
C _{TX}	AC coupling capacitor	75	_	200	nF	All transmitters shall be AC coupled. The AC coupling is required either within the media or within the transmitting component itself.



Package Description

18.2 Mechanical Dimensions of the MPC8544E FC-PBGA

Figure 59 shows the mechanical dimensions and bottom surface nomenclature of the MPC8544E, 783 FC-PBGA package without a lid.



Notes:

- 1. All dimensions are in millimeters.
- 2. Dimensions and tolerances per ASME Y14.5M-1994.
- 3. Maximum solder ball diameter measured parallel to datum A.
- 4. Datum A, the seating plane, is determined by the spherical crowns of the solder balls.
- 5. Parallelism measurement shall exclude any effect of mark on top surface of package.
- 6. Capacitors may not be present on all parts. Care must be taken not to short exposed metal capacitor pads.
- 7. All dimensions are symmetric across the package center lines, unless dimensioned otherwise.

Figure 59. Mechanical Dimensions and Bottom Surface Nomenclature of the MPC8544E FC-PBGA without a Lid



Package Description

Table 62. MPC8544E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes	
Ethernet Management Interface					
EC_MDC	AC7	0	OV _{DD}	4, 8, 14	
EC_MDIO	Y9	I/O	OV _{DD}	—	
	Gigabit Reference Clock	·			
EC_GTX_CLK125	Т2	I	LV _{DD}	—	
	Three-Speed Ethernet Controller (Gigab	it Ethernet 1)			
TSEC1_RXD[7:0]	U10, U9, T10, T9, U8, T8, T7, T6	I	LV _{DD}	—	
TSEC1_TXD[7:0]	T5, U5, V5, V3, V2, V1, U2, U1	0	LV _{DD}	4, 8, 14	
TSEC1_COL	R5	I	LV _{DD}	—	
TSEC1_CRS	Τ4	I/O	LV _{DD}	16	
TSEC1_GTX_CLK	Т1	0	LV _{DD}	—	
TSEC1_RX_CLK	V7	I	LV _{DD}	—	
TSEC1_RX_DV	U7	I	LV _{DD}	—	
TSEC1_RX_ER	R9	I	LV _{DD}	4, 8	
TSEC1_TX_CLK	V6	I	LV _{DD}	—	
TSEC1_TX_EN	U4	0	LV _{DD}	22	
TSEC1_TX_ER	ТЗ	0	LV _{DD}	—	
	Three-Speed Ethernet Controller (Gigab	it Ethernet 3)		·	
TSEC3_RXD[7:0]	P11, N11, M11, L11, R8, N10, N9, P10	I	LV _{DD}	—	
TSEC3_TXD[7:0]	M7, N7, P7, M8, L7, R6, P6, M6	0	LV _{DD}	4, 8, 14	
TSEC3_COL	M9	I	LV _{DD}	—	
TSEC3_CRS	L9	I/O	LV _{DD}	16	
TSEC3_GTX_CLK	R7	0	LV _{DD}	—	
TSEC3_RX_CLK	Р9	I	LV _{DD}	—	
TSEC3_RX_DV	P8	I	LV _{DD}	—	
TSEC3_RX_ER	R11	I	LV _{DD}	—	
TSEC3_TX_CLK	L10	I	LV _{DD}	—	
TSEC3_TX_EN	N6	0	LV _{DD}	22	
TSEC3_TX_ER	L8	0	LV _{DD}	4, 8	
DUART					
UART_CTS[0:1]	AH8, AF6	I	OV _{DD}	_	
UART_RTS[0:1]	AG8, AG9	0	OV _{DD}	—	



Thermal

Conductivity	Value	Units			
Solder and Air (29 \times 29 \times 0.58 mm)					
Кх	0.034	W/m∙K			
Ку	0.034				
Kz	12.1				





Figure 60. System Level Thermal Model for MPC8544E (Not to Scale)

The Flotherm library files of the parts have a dense grid to accurately capture the laminar boundary layer for flow over the part in standard JEDEC environments, as well as the heat spreading in the board under the package. In a real system, however, the part will require a heat sink to be mounted on it. In this case, the predominant heat flow path will be from the die to the heat sink. Grid density lower than currently in the package library file will suffice for these simulations. The user will need to determine the optimal grid for their specific case.



Figure 62 depicts the primary heat transfer path for a package with an attached heat sink mounted to a printed-circuit board.



(Note the internal versus external package resistance.)

Figure 62. Package with Heat Sink Mounted to a Printed-Circuit Board

The heat sink removes most of the heat from the device. Heat generated on the active side of the chip is conducted through the silicon and through the heat sink attach material (or thermal interface material), and finally to the heat sink. The junction-to-case thermal resistance is low enough that the heat sink attach material and heat sink thermal resistance are the dominant terms.

20.3.2 Thermal Interface Materials

A thermal interface material is required at the package-to-heat sink interface to minimize the thermal contact resistance. For those applications where the heat sink is attached by spring clip mechanism, Figure 63 shows the thermal performance of three thin-sheet thermal-interface materials (silicone, graphite/oil, floroether oil), a bare joint, and a joint with thermal grease as a function of contact pressure. As shown, the performance of these thermal interface materials improves with increasing contact pressure. The use of thermal grease significantly reduces the interface thermal resistance. The bare joint results in a thermal resistance approximately six times greater than the thermal grease joint.



Thermal

Heat sinks are attached to the package by means of a spring clip to holes in the printed-circuit board (see Figure 61). Therefore, the synthetic grease offers the best thermal performance, especially at the low interface pressure.



Figure 63. Thermal Performance of Select Thermal Interface Materials

The system board designer can choose between several types of thermal interface. There are several commercially-available thermal interfaces provided by the following vendors:

Chomerics, Inc. 781-935-4850 77 Dragon Ct. Woburn, MA 01801 Internet: www.chomerics.com Dow-Corning Corporation800-248-2481 Corporate Center P.O.Box 999 Midland, MI 48686-0997 Internet: www.dow.com Shin-Etsu MicroSi, Inc.888-642-7674 10028 S. 51st St. Phoenix, AZ 85044 Internet: www.microsi.com The Bergquist Company800-347-4572 18930 West 78th St.



System Design Information

PLL Power Supply Filtering 21.2

Each of the PLLs listed above is provided with power through independent power supply pins (AV_{DD}_PLAT, AV_{DD}_CORE, AV_{DD}_PCI, AV_{DD}_LBIU, and AV_{DD}_SRDS, respectively). The AV_{DD} level should always be equivalent to V_{DD} , and preferably these voltages will be derived directly from V_{DD} . through a low frequency filter scheme such as the following.

There are a number of ways to reliably provide power to the PLLs, but the recommended solution is to provide independent filter circuits per PLL power supply as illustrated in Figure 65, one to each of the AV_{DD} pins. By providing independent filters to each PLL the opportunity to cause noise injection from one PLL to the other is reduced.

This circuit is intended to filter noise in the PLLs resonant frequency range from a 500 kHz to 10 MHz range. It should be built with surface mount capacitors with minimum Effective Series Inductance (ESL). Consistent with the recommendations of Dr. Howard Johnson in High Speed Digital Design: A Handbook of Black Magic (Prentice Hall, 1993), multiple small capacitors of equal value are recommended over a single large value capacitor.

Each circuit should be placed as close as possible to the specific AV_{DD} pin being supplied to minimize noise coupled from nearby circuits. It should be possible to route directly from the capacitors to the AV_{DD} pin, which is on the periphery of 783 FC-PBGA the footprint, without the inductance of vias.

Figure 65 shows the PLL power supply filter circuit.



Figure 65. MPC8544E PLL Power Supply Filter Circuit

The AV_{DD}_SRDS*n* signals provide power for the analog portions of the SerDes PLL. To ensure stability of the internal clock, the power supplied to the PLL is filtered using a circuit similar to the one shown in Figure 66. For maximum effectiveness, the filter circuit is placed as closely as possible to the AV_{DD} SRDS*n* balls to ensure it filters out as much noise as possible. The ground connection should be near the AV_{DD}_SRDSn balls. The 0.003-µF capacitor is closest to the balls, followed by the 1-µF capacitor, and finally the 1- Ω resistor to the board supply plane. The capacitors are connected from AV_{DD} SRDS*n* to the ground plane. Use ceramic chip capacitors with the highest possible self-resonant frequency. All traces should be kept short, wide, and direct.



1. An 0805 sized capacitor is recommended for system initial bring-up.

